

Enhancement Mode P-Channel Power MOSFET

SOT23/PMOS/-20V/ \pm 12V/-0.65V/-5.5A/24.5m Ω

Rev_{0.8}





-20V,24.5mΩ, -5.5A, P-Channel MOSFET

1.Features

- ◆ Advanced Trench Technology
- ◆ Surface mount package

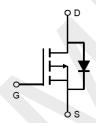
2.Applications

- ◆ Power Management
- Load Switching



SOT23 Pin Description





Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.	
WP2305ASS	2305A	SOT23	3,000	180,000	

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	-20	V
Gate to Source Voltage	V_{GSS}	±12	V
Drain Current (DC)	I_D	-5.5	А
Drain Current (Pulse), PW≤300μs	I _{DP}	-16	А
Total Dissipation	P _D	1	W
Junction Temperature	T_{j}	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	ReJA	125	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

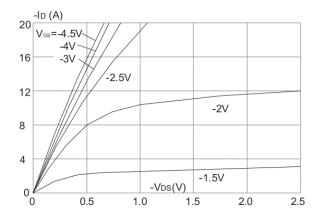
6.Electrical Characteristics at Ta=25°C (Note 3)

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = -250 \mu A$, $V_{GS} = 0 V$	-20			V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = -20V, V _{GS} = 0V			-1	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =-250μA	-0.4	-0.65	-1.2	V
Static Drain to Source On-State	_	I _D = -4A, V _{GS} =-4.5V		24.5	40	mΩ
Resistance	R _{DS(on)}	I _D = -3A, V _{GS} = -2.5V		30.5	55	mΩ
Input Capacitance	Ciss	V _{GS} =0V,		830		pF
Output Capacitance	Coss	V _{DS} =-10V,		132		pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz		85		pF
Turn-ON Delay Time	t _{d(on)}			10		ns
Rise Time	tr	V _{DS} =-10V, I _D =-3.3A,,		23		ns
Turn-OFF Delay Time	t _{d(off)}	$R_G = 1\Omega$, $V_{GEN} = -4.5V$		50		ns
Fall Time	t _f			51		ns
	Qg	V _{DS} = -10V,		8.8		nC
Total Gate Charge	Qgs	$V_{GS} = -4.5V$,		1.4		nC
	Q _{gd}	I _D = -2A		1.9		nC
Diode Forward Voltage	V _{FSD}	I _S = -4A, V _{GS} = 0	-0.4	-0.85	-1.2	V

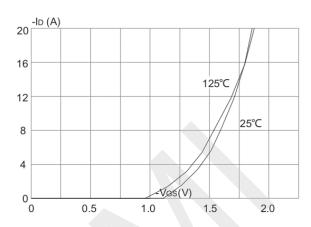
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



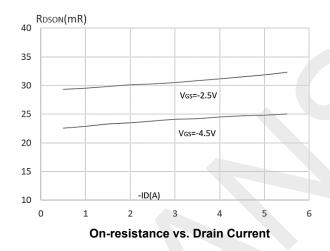
7. Typical Electrical and Thermal Characteristics

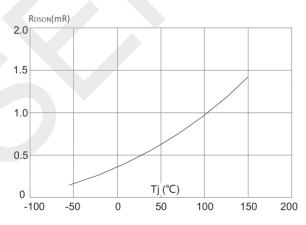


Output Characteristics

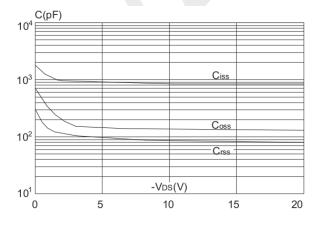


Transfer Characteristics

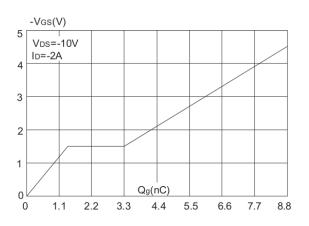




On-Resistance vs. Junction Temperature

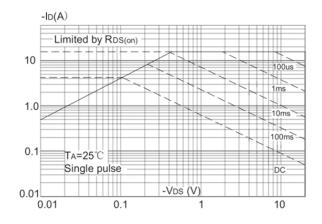


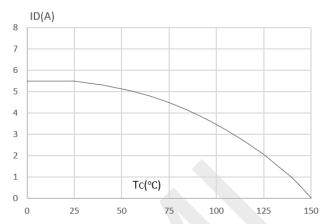
Capacitance Characteristics



Gate Charge

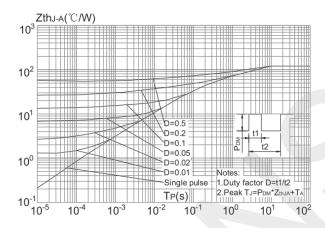






Safe Operating Area

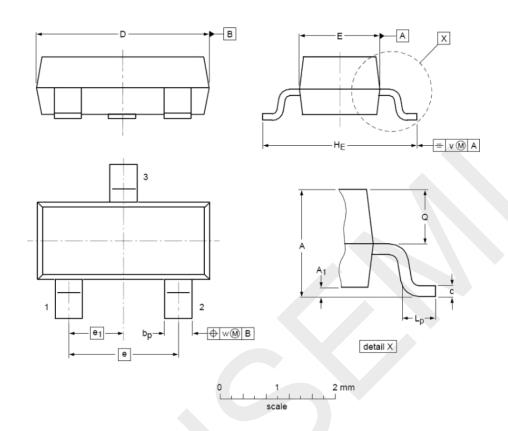
Maximum Continuous Drain Current vs.
Ambient Temperature



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



DIMENSIONS (unit : mm)

Symbol	Min	Тур	Max	Symbol	Min	Тур	Max
Α	0.90	1.01	1.15	A ₁	0.01	0.05	0.10
bp	0.30	0.42	0.50	С	0.08	0.13	0.15
D	2.80	2.92	3.00	E	1.20	1.33	1.40
е		1.90		e ₁		0.95	
HE	2.25	2.40	2.55	Lp	0.30	0.42	0.50
Q	0.45	0.49	0.55	v		0.20	
w		0.10					



9.Important Notice

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